


Search Notes 	Application/Control No. 10517316	Applicant(s)/Patent Under Reexamination TANAKA ET AL.
	Examiner Nam V Nguyen	Art Unit 2612

SEARCHED			
Class	Subclass	Date	Examiner
340	10.1; 10.2; 10.31; 10.51; 572.4; 825.69; 825.72	7/8/08	NN
342	42; 44	7/8/08	NN
235	375	7/8/08	NN
370	437	7/8/08	NN

SEARCH NOTES		
Search Notes	Date	Examiner
Search EAST: USPAT; US-PUB; EPO; JPO; DERWENT. (UPDATED SEARCH).	7/8/08	NN
Search Terms: rfid; rags or transponders with range distance reading, zones, reading id range.	7/8/08	NN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
SAME	AS ABOVE.	7/8/08	NN